

Electronic Supplementary Information for

Oxygen-induced degradation in AgBiS₂ nanocrystal solar cells

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- Fig. S1 Photovoltaic parameters after two days dark storage of devices with four different combination of extraction layers.
- Fig. S2 Light-intensity-dependent measurements of the V_{OC} of a ZnOsg & PTAA:C₆₀F₄₈ AgBiS₂ NC SC.
- Fig. S3 Transient absorption spectra for degrading AgBiS₂ films and their normalised kinetics.
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- Fig. S13 XPS measurements of Ag electrodes of degraded AgBiS₂ NC solar cells.
- Fig. S14 Environmental gas stability for ZnOnp/AgBiS₂/PTAA:C₆₀F₄₈ devices under continuous 1 sun irradiation.
- Fig. S15 J_{SC} evolution in dry air for different preconditions for ITO/ZnOsg/AgBiS₂-TMAI/PTAA:C₆₀F₄₈/Ag devices.

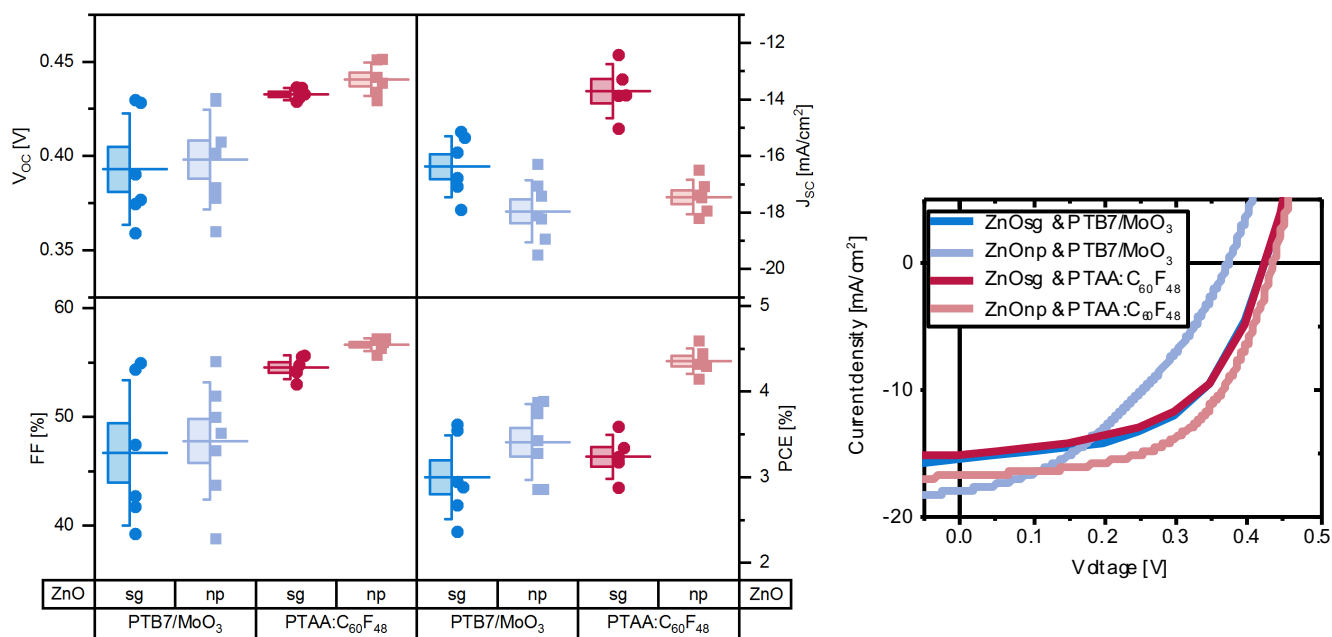


Fig. S1 left: Photovoltaic parameters after two days of dark storage, measured with 1 sun intensity for the four different combination of extraction layers and on the right: the JV-curves of the best performing devices for each case.

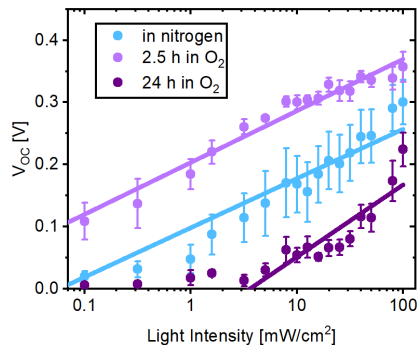


Fig. S2 Light-intensity-dependent measurements of the V_{oc} of a ZnOsg & PTAA:C₆₀F₄₈ AgBiS₂ NC SC. The first assessment is performed in nitrogen. Afterwards 20% oxygen are added to the gas flow and in the denoted time frames the second and third measurement are conducted.

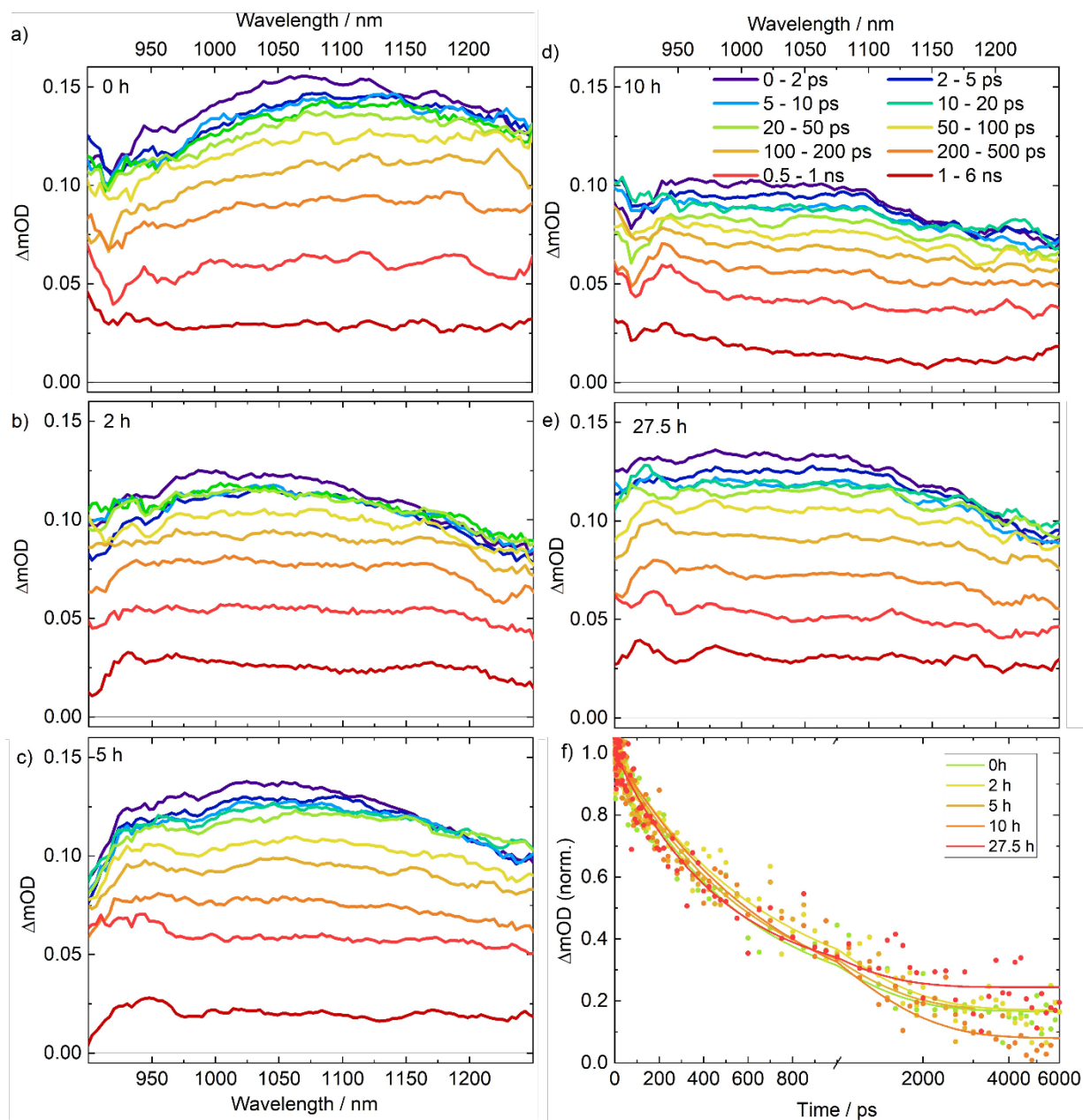


Fig. S3 a-e) transient absorption spectra for neat AgBiS₂ films at increasing extents of degradation, following excitation with a 700 nm pump pulse. f) Normalised kinetics averaged across PIA region for each film with monoexponential fits shown as solid lines.

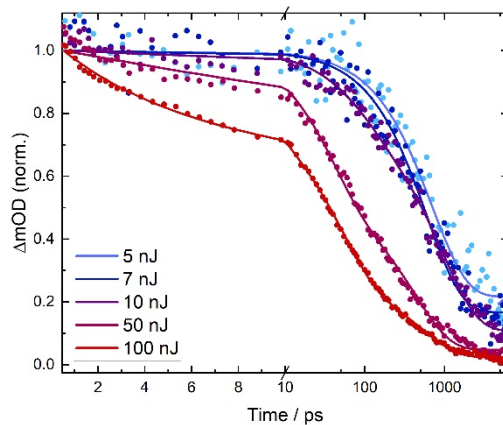


Fig. S4 Dependence of the normalised near-infrared (NIR) TA kinetics on pump intensity averaged across PIA region with a 700 nm pump wavelength. Solid lines are multiexponential fits.

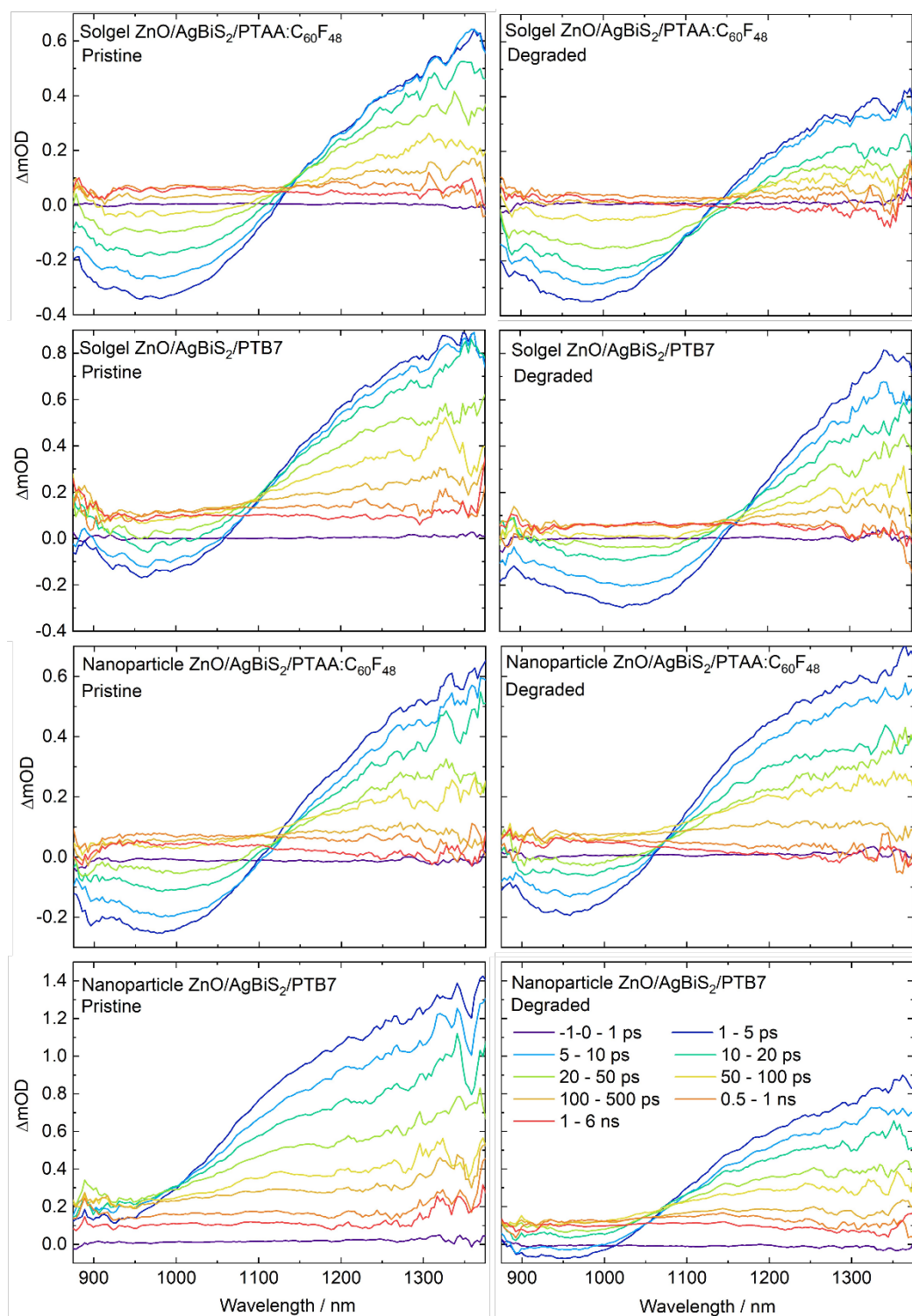


Fig. S5 TA spectra for AgBiS₂ devices (pumped at 700 nm) with different hole and electron transport layers, both pristine (left) and following 8 hours of degradation under light and O₂ (right).

Table S1 Atomic percentages of pristine and 24h, 20% oxygen and light degraded, 30 nm thick AgBiS₂-TMAI NC film on a glass/gold substrate, extracted from Fig. 2.

Orbital	Atomic % (pristine)	Atomic % (degraded)
C 1s	39.2	43.9
Ag 3d	19.6	15.1
Bi 4f	8.9	7.8
S 2p	12.1	5.5
I 3d	7.4	4.7
O 1s	11.6	20.2
Au 4f	1.2	2.9

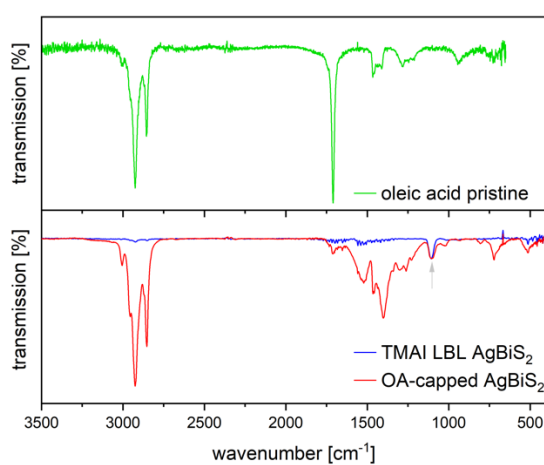


Fig. S6 FTIR measurements on TMAI and OA capped AgBiS₂ NCs. FTIR of OA is provided as reference.

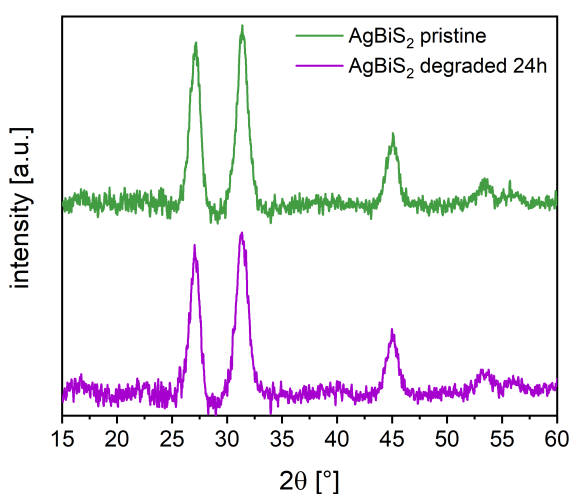


Fig. S7 XRD measurements of pristine and 24h, 20% oxygen and light degraded, AgBiS₂-TMAI NC films.

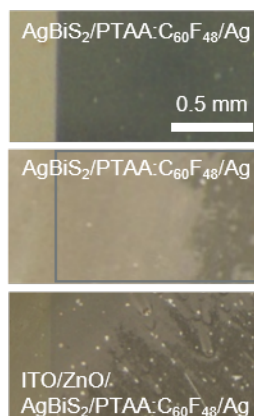


Fig. S8 Microscope images of the silver electrode (darker area) on AgBiS₂ NC films. Top: pristine state, the lighter part on the left is the uncovered AgBiS₂ NC film. Middle: degraded state after 24 h in oxygen and light, the original electrode extension is outlined. Bottom: degraded state of a full device after 24 h in oxygen and light.

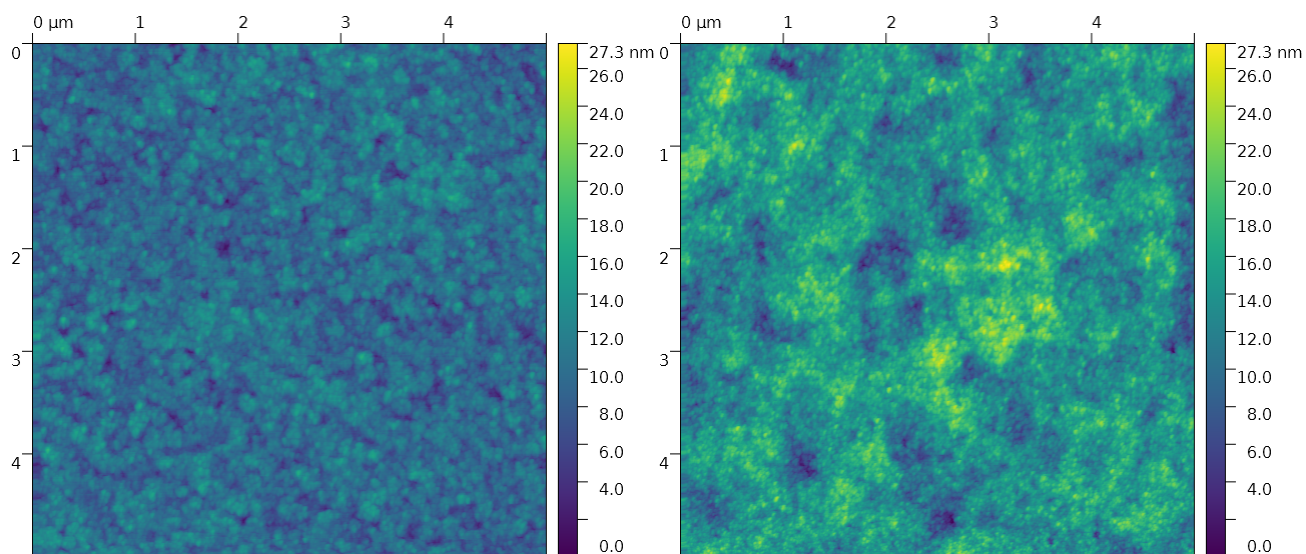


Fig. S9 Atomic force microscopy (AFM) micrographs of two different ZnO configurations (left: sg, right: np) on glass/ITO.

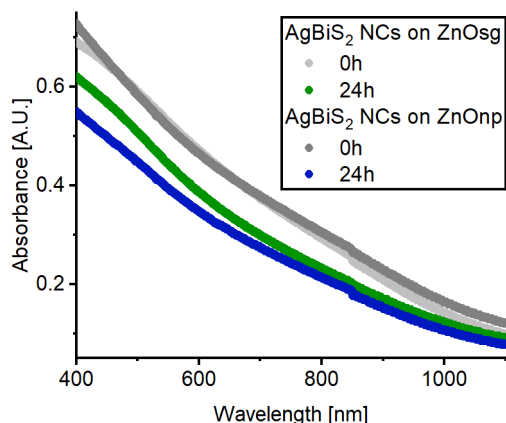


Fig. S10 Absorption measurements during degradation of an AgBiS₂ film on top of a ZnOsg and np film. The degradation was performed in dry air and light. Compared to Fig. 5 the absorption loss is enhanced, especially on ZnOnp. The small step at 850nm is caused by a change of grating within the measurement setup.

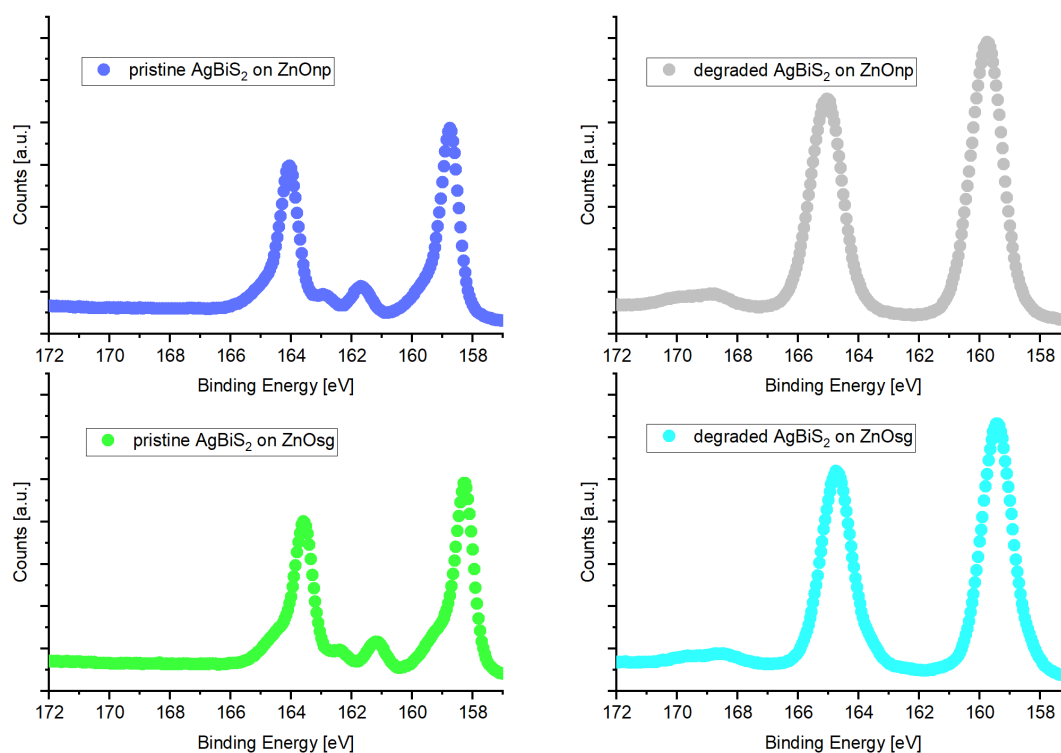


Fig. S11 XPS data of the Bi 4f orbital as a measure of the compositional degradation of a layer of AgBiS₂ NCs on ITO/ZnOxx during degradation. Compared to Fig. 5 the degradation after 24 h in dry air and light appears more severe, manifesting in more oxidised species.

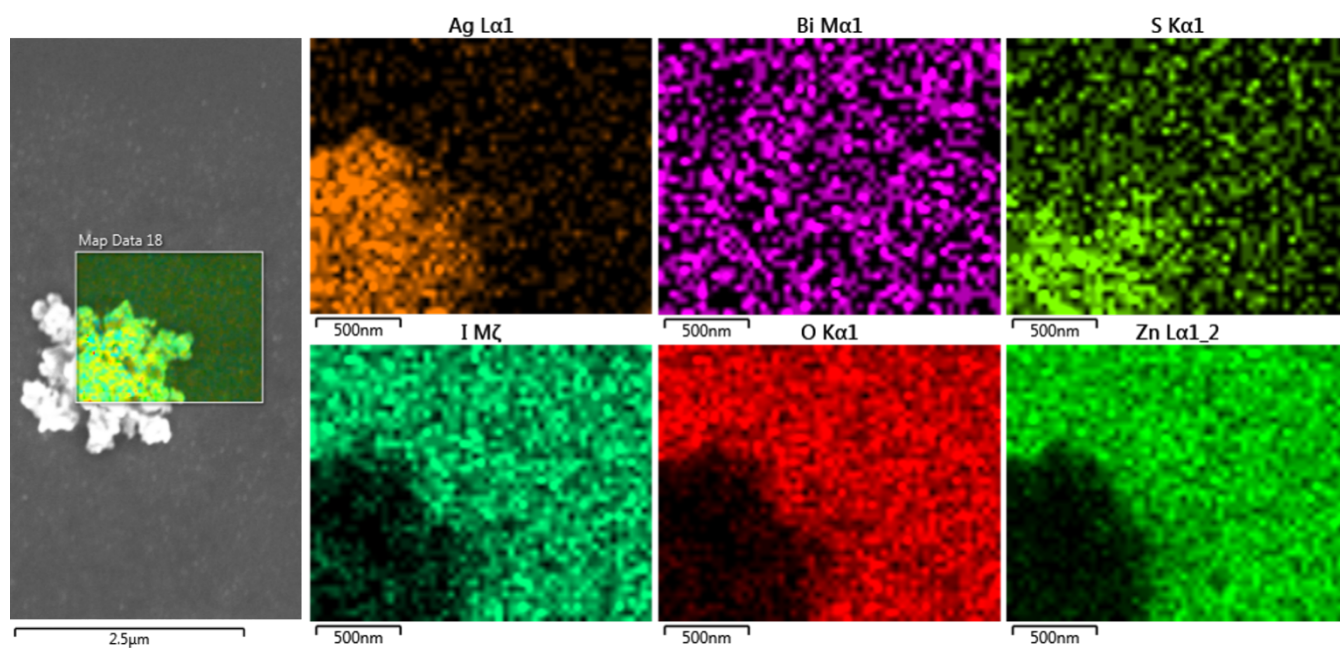


Fig. S12 EDX measurement of a aggregates appearing on the AgBiS_2 NC films deposited on a ZnOnc layer.

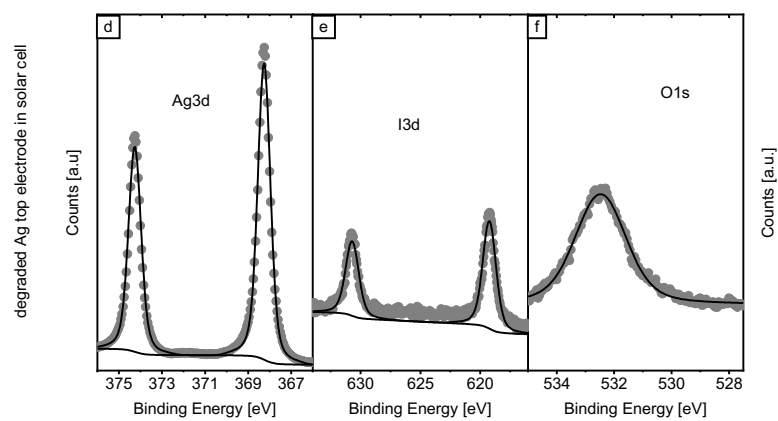


Fig. S13 XPS measurements of Ag electrodes of degraded AgBiS_2 NC solar cells.

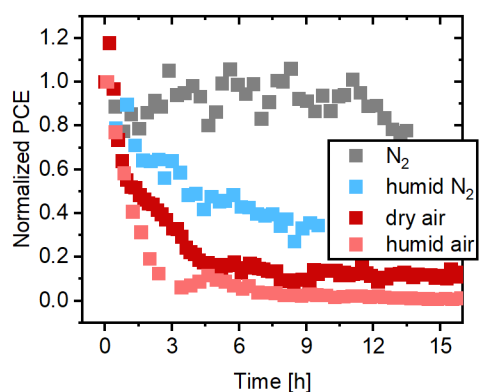


Fig. S14 Environmental stability for ZnOnp/AgBiS₂/PTAA:C₆₀F₄₈ devices under continuous 1 sun irradiation in different atmospheres. The data was normalized to the first measurement value.

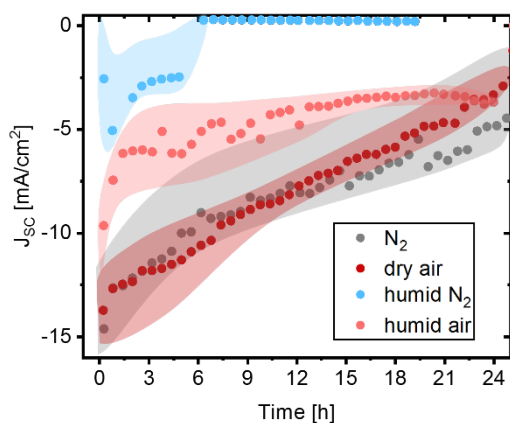


Fig. S15 J_{sc} evolution in dry air for different preconditions for ITO/ZnOsg/AgBiS₂-TMAI/PTAA:C₆₀F₄₈/Ag devices. Preconditioning was carried out for two days in the dark. The transparent shades denote the standard error of the averaged values.